FAIRCHILD

SEMICONDUCTOR®

November 2013

FQD5N20L **N-Channel QFET® MOSFET** 200 V, 3.8 A, 1.2 Ω

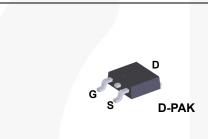
Description

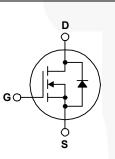
This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance . Low Crss (Typ. 6.0 pF) and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power • 100% Avalanche Tested factor correction (PFC), and electronic lamp ballasts.

Features

- 3.8 A, 200 V, $R_{DS(on)}$ = 1.2 Ω (Max.) @ V_{GS} = 10 V, I_D = 1.9 A
- Low Gate Charge (Typ. 4.8 nC)

- · RoHS Compliant





Absolute Maximum Ratings T_c = 25°C unless otherwise noted.

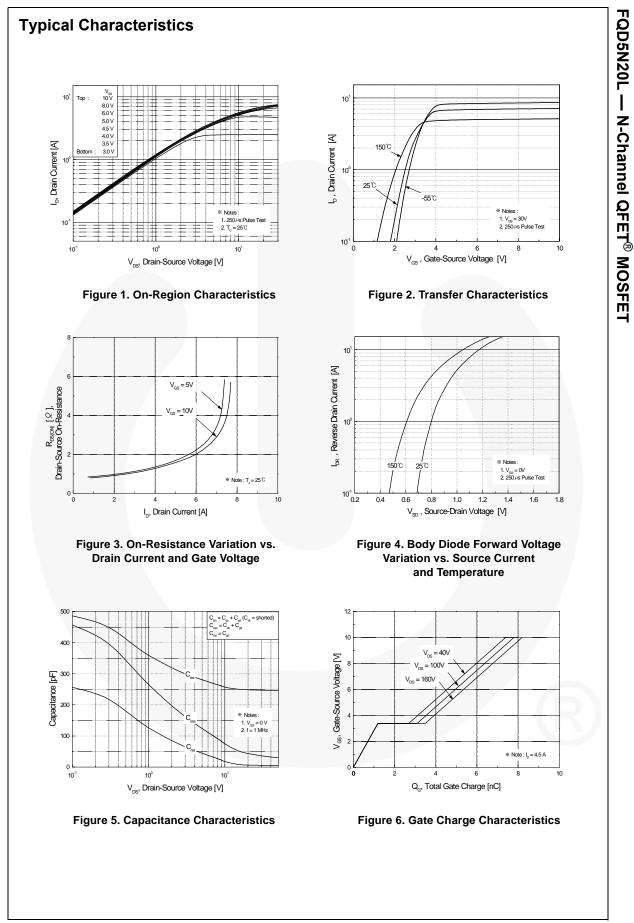
Symbol	Parameter	FQD5N20LTM	Unit
V _{DSS}	Drain-Source Voltage	200	V
I _D	Drain Current - Continuous ($T_C = 25^{\circ}C$)	3.8	A
	- Continuous (T _C = 100°C)	2.4	A
I _{DM}	Drain Current - Pulsed (Note 1)	15.2	А
V _{GSS}	Gate-Source Voltage	± 20	V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)	60	mJ
I _{AR}	Avalanche Current (Note 1)	3.8	A
E _{AR}	Repetitive Avalanche Energy (Note 1)	3.7	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	5.5	V/ns
P _D	Power Dissipation (T _A = 25°C) *	2.5	W
-	Power Dissipation (T _C = 25°C)	37	W
	- Derate above 25°C	0.29	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +150	°C
TL	Maximum lead temperature for soldering,1/8" from case for 5 seconds	300	°C

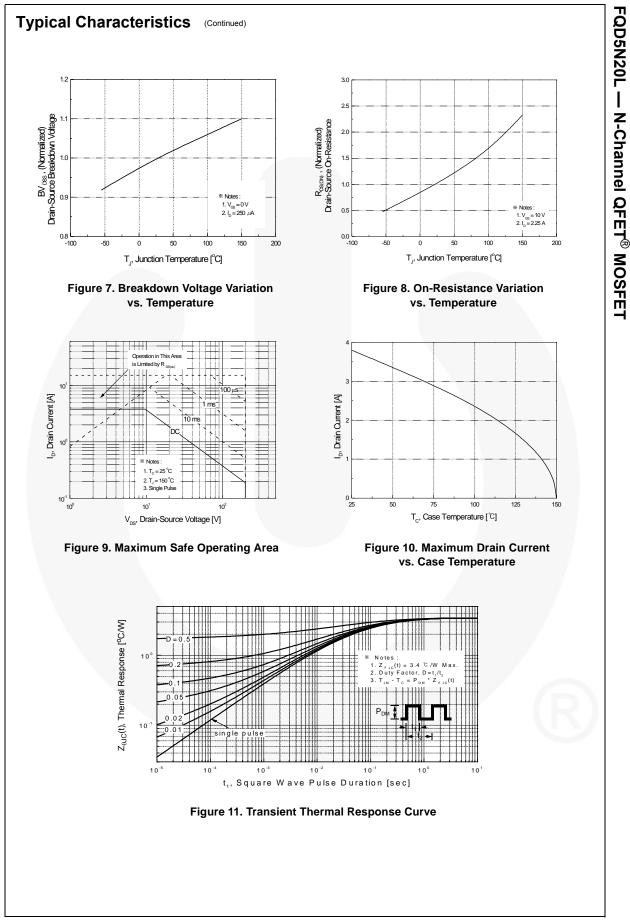
Thermal Characteristics

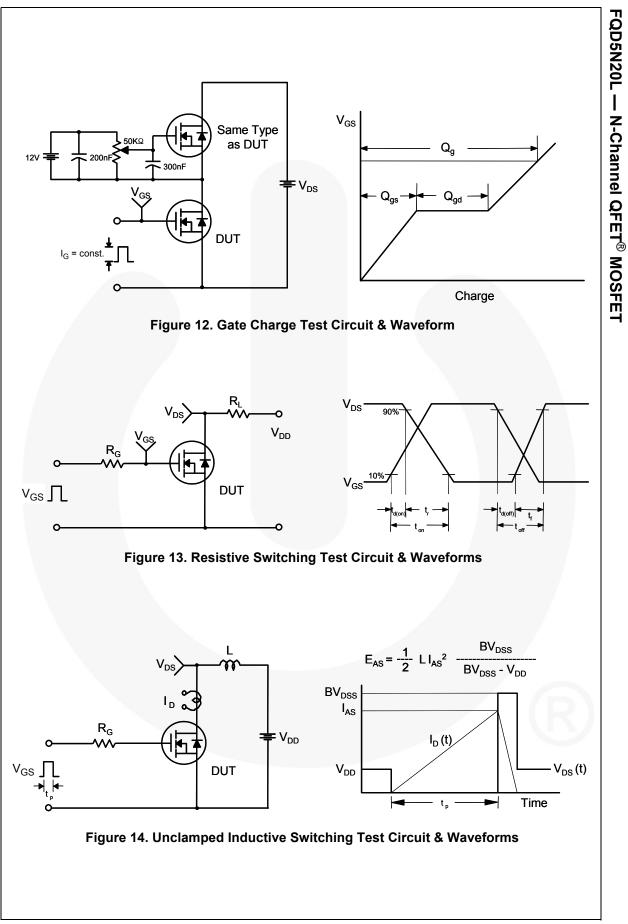
Symbol	Parameter	FQD5N20LTM	Unit
R_{\thetaJC}	Thermal Resistance, Junction to Case, Max.	3.4	
$R_{ hetaJA}$	Thermal Resistance, Junction to Ambient (Minimum Pad of 2-oz Copper), Max.	110	°C/W
	Thermal Resistance, Junction to Ambient (*1 in ² Pad of 2-oz Copper), Max.	50	

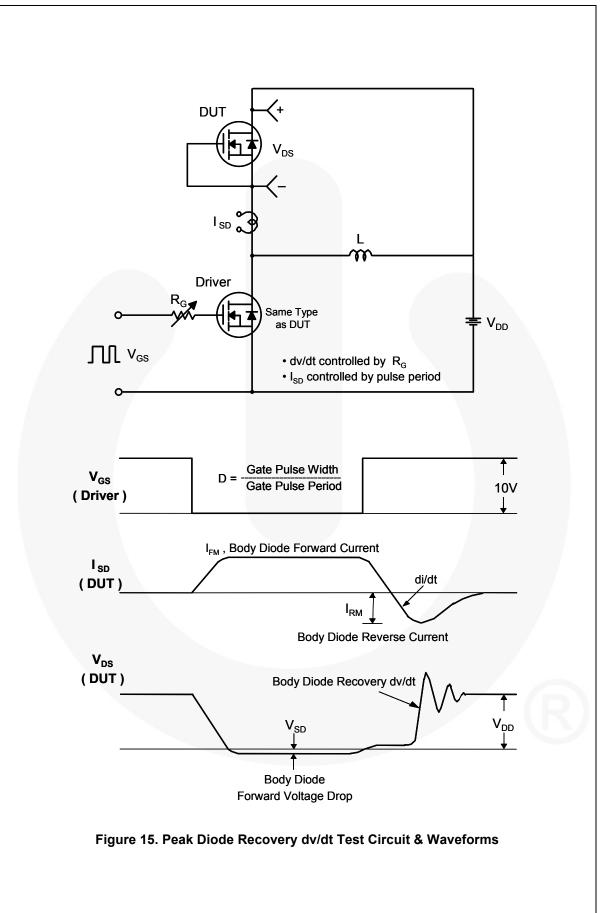
Part Number Top Mark Pag		Pack	age	Packing Method	Reel	Size	Tape W	idth	Quantity	
FQD5	•				330	mm	16 mm		2500 units	
lectric	al Cha	racteristics	T _C = 25°0	C unless othe	erwise noted.					
Symbol		Parameter			Test Conditions		Min.	Тур.	Max	. Unit
Off Cha	racterist	ics		1						
3V _{DSS}	Drain-Sou	rce Breakdown Vo	Itage	$V_{GS} = 0$) V, I _D = 250 μA		200			V
ΔBV _{DSS} / ΔT _J		Breakdown Voltage Temperature		$I_D = 250 \ \mu$ A, Referenced to 25°C			0.18		V/°C	
DSS		Zero Gate Voltage Drain Current		$V_{DS} = 200 V, V_{GS} = 0 V$ $V_{DS} = 160 V, T_C = 125^{\circ}C$				1	μA	
	Gate-Body Leakage Current, Forward		50	3				10	μΑ	
GSSF					$20 \text{ V}, \text{ V}_{\text{DS}} = 0 \text{ V}$				100	nA
GSSR	Gate-Body	y Leakage Current,	Reverse	v _{GS} = -	20 V, V _{DS} = 0 V				-100	nA
On Cha	racterist	ics								
V _{GS(th)}	Gate Thre	shold Voltage			/ _{GS} , I _D = 250 μA		1.0		2.0	V
R _{DS(on)}	Static Drai		_	00	10 V, I _D = 1.9 A			0.94	1.2	Ω
	On-Resist				5 V, I _D = 1.9 A			0.98	1.25	
JFS	Forward T	ransconductance	_	V _{DS} = 3	80 V, I _D = 1.9 A			3.35		S
Dynami	c Charac	teristics								
C _{iss}	Input Capa	acitance		V _{DS} = 25 V, V _{GS} = 0 V,				250	325	pF
C _{oss}	Output Ca	pacitance		50	f = 1.0 MHz			40	50	pF
C _{rss}	Reverse T	ransfer Capacitand	ce					6	8	pF
Switchi	ng Chara	acteristics		1						
d(on)	Turn-On D		_	$\lambda = -1$	100 V, I _D = 4.5 A,			9	25	ns
r	Turn-On R	Rise Time		$R_{G} = 25$	-			90	190	ns
d(off)	Turn-Off D	elay Time			522			15	40	ns
f	Turn-Off F	all Time				(Note 4)		50	110	ns
ე _g	Total Gate	Charge		Vne = 1	60 V, I _D = 4.5 A,			4.8	6.2	nC
Q _{gs}	Gate-Sour	ce Charge		$V_{GS} = 5$				1.2		nC
ຊ _{gd}		Gate-Drain Charge		00 -	(Note 4)		-	2.4		nC
Drain-S	ource Di	ode Character	istics ar	nd Max	imum Ratings					
s		Continuous Drain-			U				3.8	Α
SM	Maximum	Pulsed Drain-Sour	ce Diode F	orward C	Current				15.2	А
/ _{SD}		rce Diode Forward		1) V, I _S = 3.8 A				1.5	V
rr.		Recovery Time	Ŭ) V, I _S = 4.5 A,			95	-	ns
2 ^m	Reverse F	Recovery Charge		00	= 100 A/μs			0.3		μC
. L = 6.2 mH,	I_{AS} = 3.8 A, V_E di/dt \leq 300 A/µ	dth limited by maximum j $_{DD}$ = 50 V, R _G = 25 Ω, sta s, V _{DD} ≤ BV _{DSS} , starting operating temperature.	irting $T_J = 25^\circ$							K

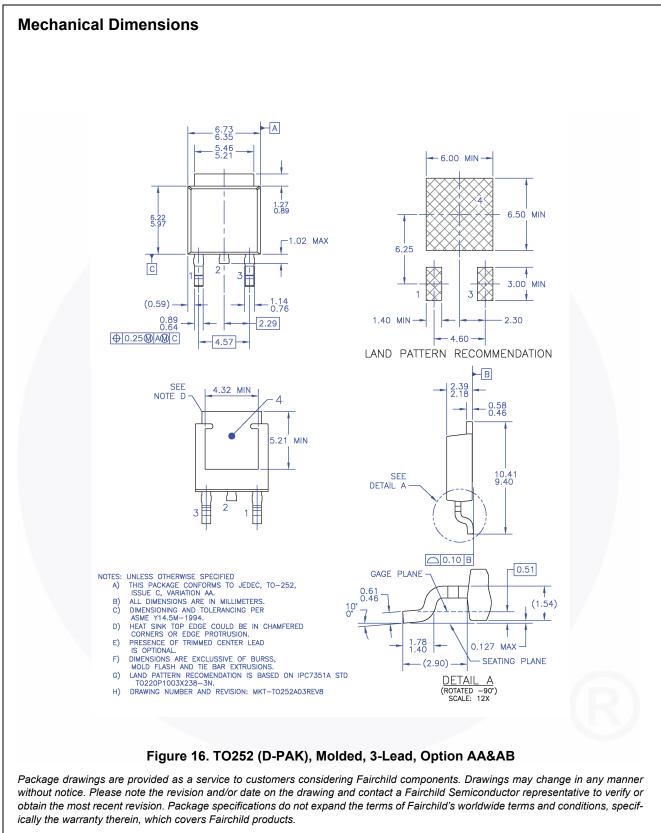
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Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.
		Rev. 166

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